PROCEEDINGS OF SPIE

SPIDigitalLibrary.org/conference-proceedings-of-spie

Study of Electric Field Enhancement Caused by Debris on Laser Optics (Withdrawal Notice)

Hu Huang, Kyle Kafka, Stavros Demos

Hu Huang, Kyle Kafka, Stavros Demos, "Study of Electric Field Enhancement Caused by Debris on Laser Optics (Withdrawal Notice)," Proc. SPIE 11514, Laser-induced Damage in Optical Materials 2020, 115141A (18 September 2020); doi: 10.1117/12.2571062

SPIE.

Event: SPIE Laser Damage, 2020, Online Only

Study of Electric Field Enhancement Caused by Debris on Laser Optics (Withdrawal Notice)

Hu Huang, Kyle Kafka, Stavros Demos

Univ. of Rochester (United States)

Proceedings Volume 11514, Laser-induced Damage in Optical Materials 2020; 115141A (2020)
<https://doi.org/10.1117/12.2571062>

Event: SPIE Laser Damage, 2020, Online Only

Online Publication Date: 11 September 2020

Withdrawn from Publication: 18 September 2020

Publisher's Note: This presentation, originally published on 11 September 2020, was withdrawn per author request.